

Measurement Report for System Check_2450MHZ (2450.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	SN	DUT Type
Device,	50.0 x 10.0 x 8.0	919	D2450V2

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0-	2450.000, 0	7.29	1.87	39.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V5.0 (20deg probe tilt) - 1128	2300-2700MHZ-0508	EX3DV4 - SN7693, 2025-11-26	DAE4 Sn1390, 2025-11-19

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-05-08	2026-05-08
psSAR1g [W/kg]	5.26	5.11
psSAR10g [W/kg]	2.51	2.37
Power Drift [dB]	-0.09	-0.14
Power Scaling	Disabled	Disabled
Scaling Factor		
[dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.7
Dist 3dB Peak [mm]		9.0

